## **Supplementary Page**

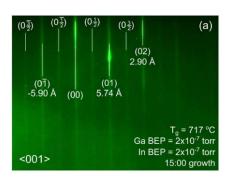


Figure S1: RHEED image typical of In-catalyzed Ga<sub>2</sub>O<sub>3</sub> growth

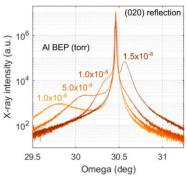


Figure S2: X-ray diffraction of (Al,In,Ga)<sub>2</sub>O<sub>3</sub> alloys grown at various Al flux values.

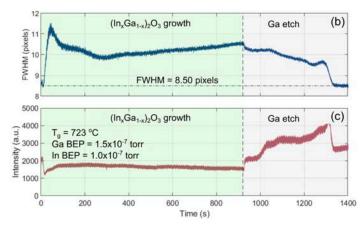


Figure S3: FWHM and intensity of the specular RHEED reflection during the growth and etchback process.

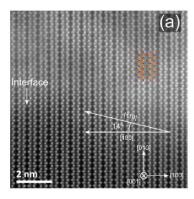


Figure S4: Scanning transmission electron microscopy (STEM) demonstrating betaphase (Al<sub>0.17</sub>Ga<sub>0.76</sub>In<sub>0.07</sub>)<sub>2</sub>O<sub>3</sub>

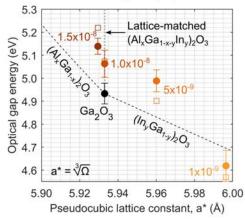


Figure S5: Spectroscopic ellipsometry Tauc analysis of (Al,In,Ga)<sub>2</sub>O<sub>3</sub> optical absorption onset.

## References:

- [1] S. Schaefer, J. Mater. Chem. A, 12, 5508(2024).
- [2] S. Schaefer, Appl. Phys. Lett., 125, 172106 (2024)